

Enhancement Mode N-Channel Power MOSFET

SOT23-3/NMOS/100V/ \pm 20V/1.5V/4A/84m Ω

Rev1.2





100V, 84mΩ, 4A, Single N-Channel

1.Features

- ◆ 100V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±20V

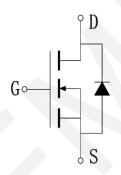
2.Applications

- Power Switching Application
- Load Switching



Pin Description

V _{DS}	R _{DS(on)} Typ.	I _D Max.	
400)/	84mΩ @ 10V	4.0	
100V	90mΩ @4.5V	4A	



Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WP1004S3	1004	SOT23-3	3,000	180,000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V _{DSS}	100	V
Gate to Source Voltage	V_{GSS}	±20	V
Drain Current (DC)	ID	4	А
Drain Current (Pulse), PW≤300μs	I _{DP}	16	А
Total Dissipation	P _D	1.2	W
Junction Temperature	Tj	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5.Thermal Resistance Ratings (Note 2)

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Ambient	ReJA	158	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

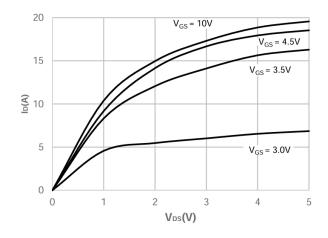
6.Electrical Characteristics at Ta=25°C (Note 3)

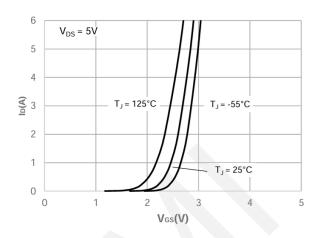
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A$, $V_{GS} = 0 V$	100	-	-	V
Zero-Gate Voltage Drain Current	I _{DSS}	V _{DS} = 100V, V _{GS} = 0V	-	1	1	μΑ
Gate to Source Leakage Current	Igss	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	V _{DS} =V _{GS} , I _{DS} =250µA	1.0	1.5	2.5	V
Static Drain to Source On-State	Б	I _D = 4A, V _{GS} =10V	-	84	105	mΩ
Resistance	R _{DS(on)}	I _D = 3A, V _{GS} = 4.5V	1	90	125	mΩ
Input Capacitance	C _{iss}	V _{GS} =0V,	-	818	-	pF
Output Capacitance	Coss	V _{DS} =50V,	-	31	-	pF
Reverse Transfer Capacitance	Crss	Frequency=1.0MHz	-	25	-	pF
Turn-ON Delay Time	t _{d(on)}		ı	5.4	-	ns
Rise Time	tr	$V_{DD} = 50V, I_{D} = 4A$	-	3.9	-	ns
Turn-OFF Delay Time	$t_{\sf d(off)}$	$V_{GS} = 10V, R_G = 6.2\Omega$	-	23	-	ns
Fall Time	t _f		1	2.6	-	ns
	Qg	V _{DS} = 50V, V _{GS} =0 to 10V,	-	20	-	nC
Total Gate Charge	Qgs		-	2.9	-	nC
	Q _{gd}	I _D = 4A	-	4.4	-	nC
Diode Forward Voltage	V_{FSD}	I _S = 4A, V _{GS} = 0V	0.5	-	1.2	V

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

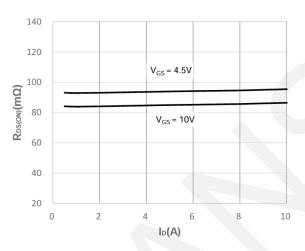


7. Typical Electrical and Thermal Characteristics

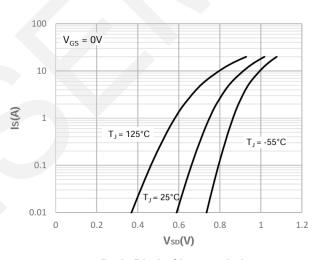




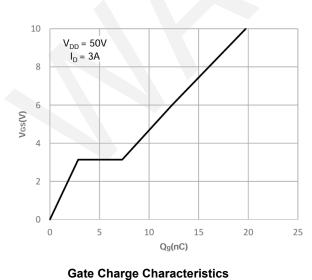
Output Characteristics



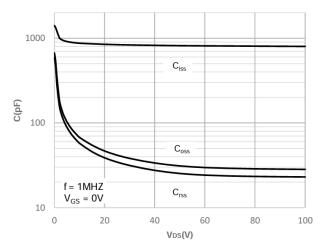
Typical Transfer Characteristics



On-resistance vs. Drain Current

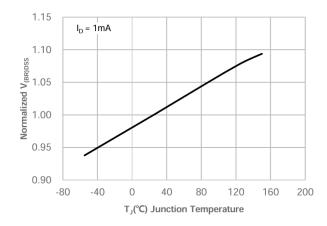


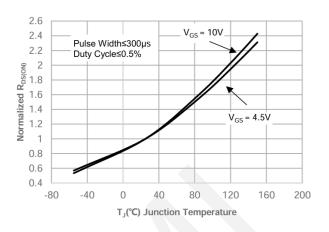
Body Diode Characteristics



Capacitance Characteristics





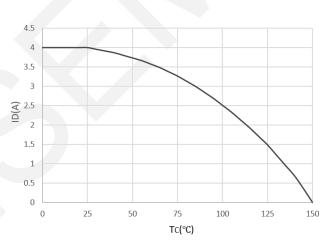


Normalized Breakdown Voltage vs. Junction Temperature

100 Limited by R_{DS(ON)} 10 10us 100us 1ms 10ms 0.1 0.01 $T_A = 25^{\circ}C$ DC Single Puse 0.001 0.1 10 100 V_{DS}(V)

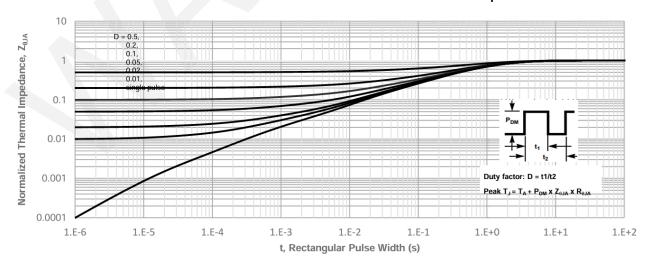
Maximum Safe Operating Area

Normalized on Resistance vs. Junction Temperature



Maximum Continuous Drain Current vs.

Case Temperature

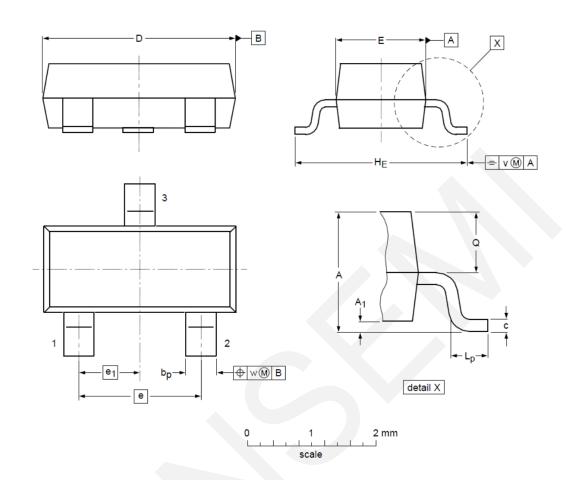


Maximum Effective Transient

Thermal Impedance, Junction-to-Case



8.Package Dimensions



DIMENSIONS (unit : mm)

Symbol	Min	Тур	Max	Symbol	Min	Тур	Max
Α	1.00	1.17	1.30	A ₁	0.01	0.05	0.10
b _P	0.35	0.39	0.50	С	0.10	0.20	0.26
D	2.70	2.90	3.10	E	1.30	1.58	1.70
е		1.90		e ₁		0.95	
HE	2.50	2.78	3.00	L _p	0.20	0.32	0.60
Q	0.23	0.27	0.33	v		0.20	
w		0.20					



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